



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Shunpei Yamazaki et al. Art Unit : Unknown
Serial No. : 10/647,539 Examiner : Unknown
Filed : August 26, 2003
Title : SEMICONDUCTOR THIN FILM AND ITS MANUFACTURING METHOD
AND SEMICONDUCTOR DEVICE AND ITS MANUFACTURING METHOD

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Supplemental to an information disclosure statement filed with the application on August 26, 2003, Applicants submit the reference listed on the attached form PTO-1449.

This statement is being filed before the receipt of a first Office action on the merits.

Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: February 2, 2004


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Substitute Form PTO-1449
(Modified)U.S. Department of Commerce
Patent and Trademark OfficeAttorney's Docket No.
07977-126004Application No.
10/647,539**Information Disclosure Statement
by Applicant**

(Use several sheets if necessary)

Applicant
Shunpei Yamazaki et al.Filing Date
August 26, 2003

Group Art Unit

U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL	08-255916	10/01/1996	JAPAN			Full	
	AM							
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	AQ	
	AR	
	AS	
	AT	

Examiner Signature

Date Considered

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.